

# Gradient Techniques For Nanotechnology Development

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**NIST**

Combinatorial  
Methods Center

[www.nist.gov/combi](http://www.nist.gov/combi)

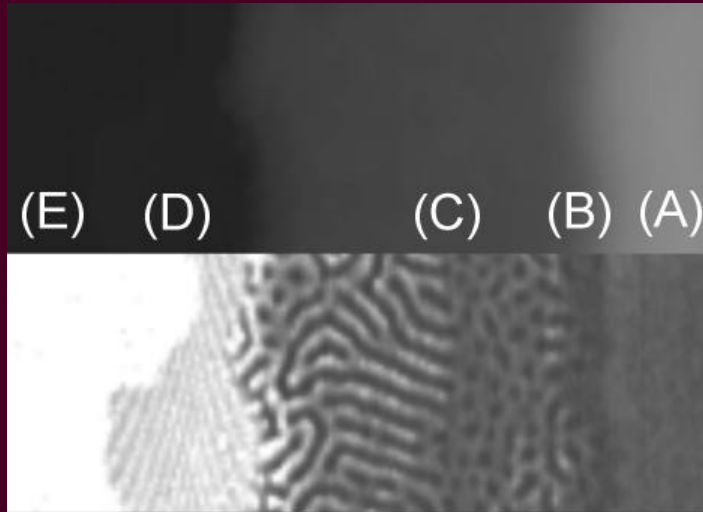
ACS NERM: June 16, 2003

# An “impromptu” gradient experiment

## Thin film morphology of PS-PLMA block copolymer

M.J. Fasolka and A.M. Mayes et al, Macromolecules **33** 5702 (2000)

AFM  
height



AFM  
phase



- AFM of droplet edge
- Morphology/thickness relationships

### Advantages:

- Illuminates morphology/thickness relationship *in a single micrograph*
- Single high-info specimen with uniform processing

### Drawbacks:

- Generally *Qualitative*
- Limited specimen scope
  - steep gradient
- Hard to reproduce

# Building Better Gradient Techniques



**NIST**

**Combinatorial  
Methods Center**

[www.nist.gov/combi](http://www.nist.gov/combi)

- Combi and high-throughput methods for *Materials Research*
- 21 Member industrial consortium
- Education and Outreach

## Continuous Gradient Specimens



- Gradual and steady change in a property as a function of distance

## NCMC Gradient Specimens

- Properties of interest to materials researchers
- Tailored gradient scope and steepness
- Reproducible fabrication

## Crossed-Gradient Combinatorial Libraries

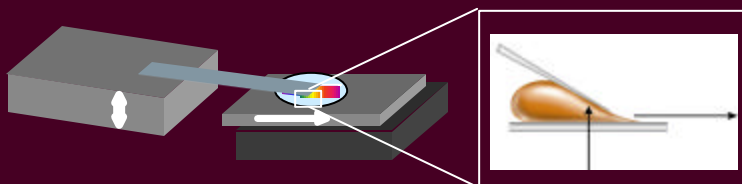


- Orthogonal arrangement of 2 gradient specimens
- Includes every combination of 2 variables within scope of gradients

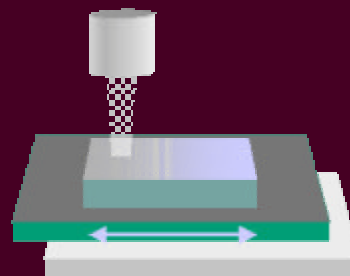
# NCMC Gradient Toolbox



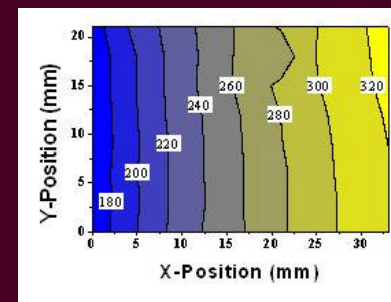
## Polymer Film Thickness Gradient (C. Meredith)



NIST Gradient Flow Coater for dilute polymer solutions

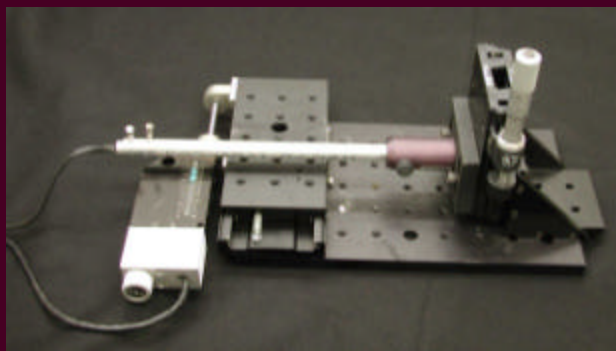


Automated Spot Interferometer

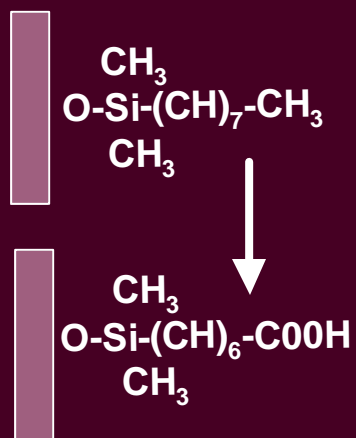


Gradient Range:  
20-500nm in 100 nm steps

## Surface Energy Gradient (A. Sehgal, A. Crosby, M. Fasolka)

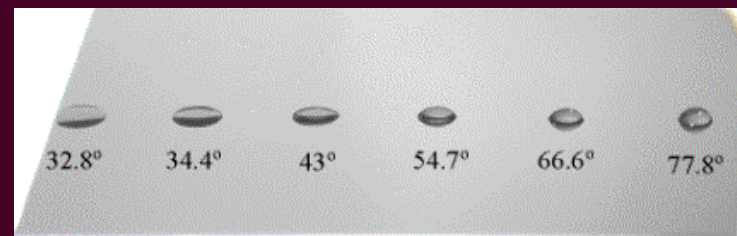


UV-ozone Exposure Gradient Device



Exposure dependent SAM conversion

Automated contact  $\angle$  measurements

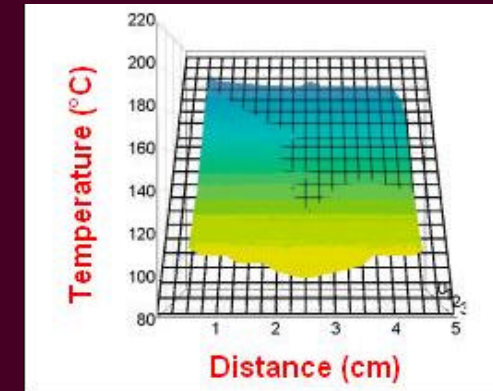
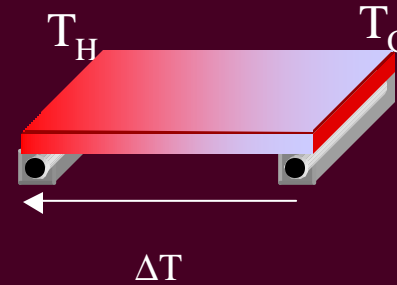
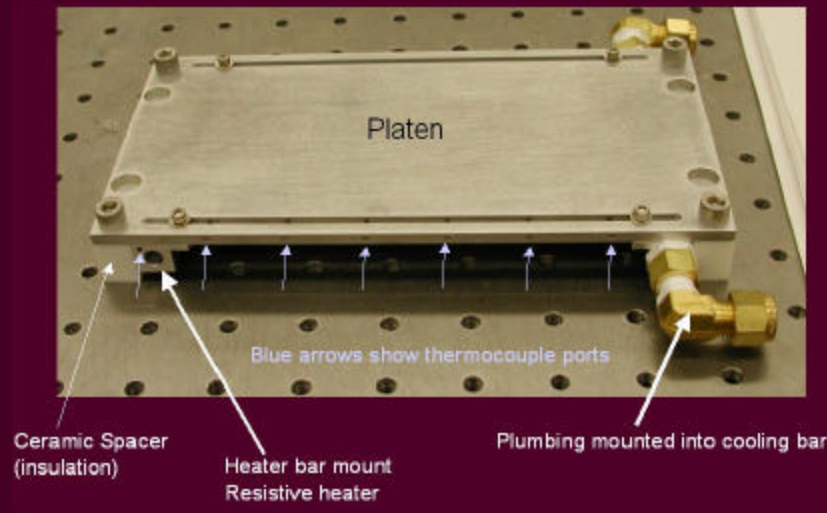


Gradient Range:  
20-78 mJ/m<sup>2</sup>  
Continuous or step-like

# NCMC Gradient Toolbox

## Temperature Gradient (K. Beers, C. Stafford)

### Gradient Hot-stage



Gradient Range:  
20 °C to 250 °C in 100 °C steps

## Other Gradients and Gradients in Development

- Composition Gradients (Polymers, Additives from Dilute Solution)
- Surface Texture Gradients (Patterned and Random Roughness)
- Cross-linking Gradients

# Gradient Applications in Nanotechnology

## Examples from NCMC Research

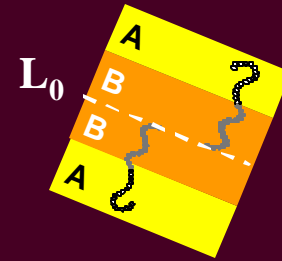
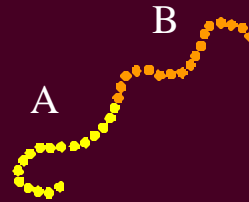
- Thorough Behavior Mapping  
*Ultra-high information density specimens*
- Process or Parameter Optimization  
*Precise determination of best conditions*
- Advancement of Nano-scale Measurements  
*Reference Substrates for Advanced SPM Techniques*



# Block Copolymer (BC) Thin Film Basics

Review: M.J. Fasolka & A.M. Mayes, Annu. Rev. Mat. Sci. 31, 323 (2001)

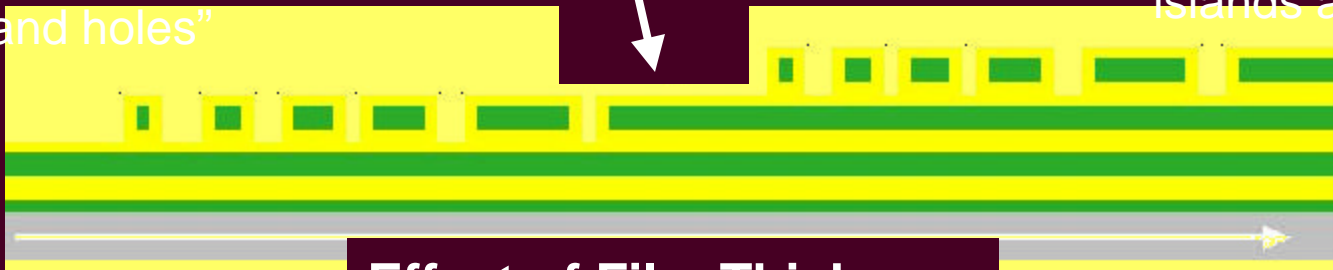
- Nanometric self assembly
  - $L_0 = 10\text{nm} - 100\text{nm}$
- Surface Directed Morphology



Surface structure:  
“islands and holes”

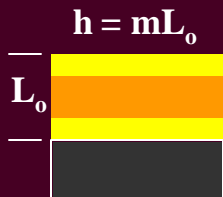
Smooth film:  
 $h = nL_0, (m+1/2)L_0$

Surface structure:  
“islands and holes”

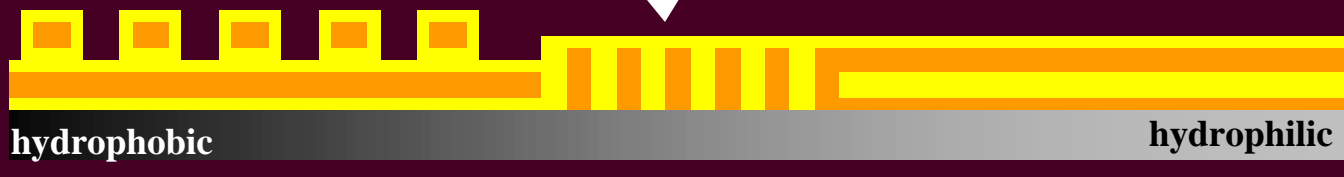


Effect of Film Thickness

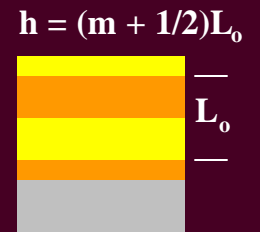
Symmetric  
wetting



Neutral surface:  
perpendicular domains



Anti-Symmetric  
wetting



Effect of Substrate Surface Energy

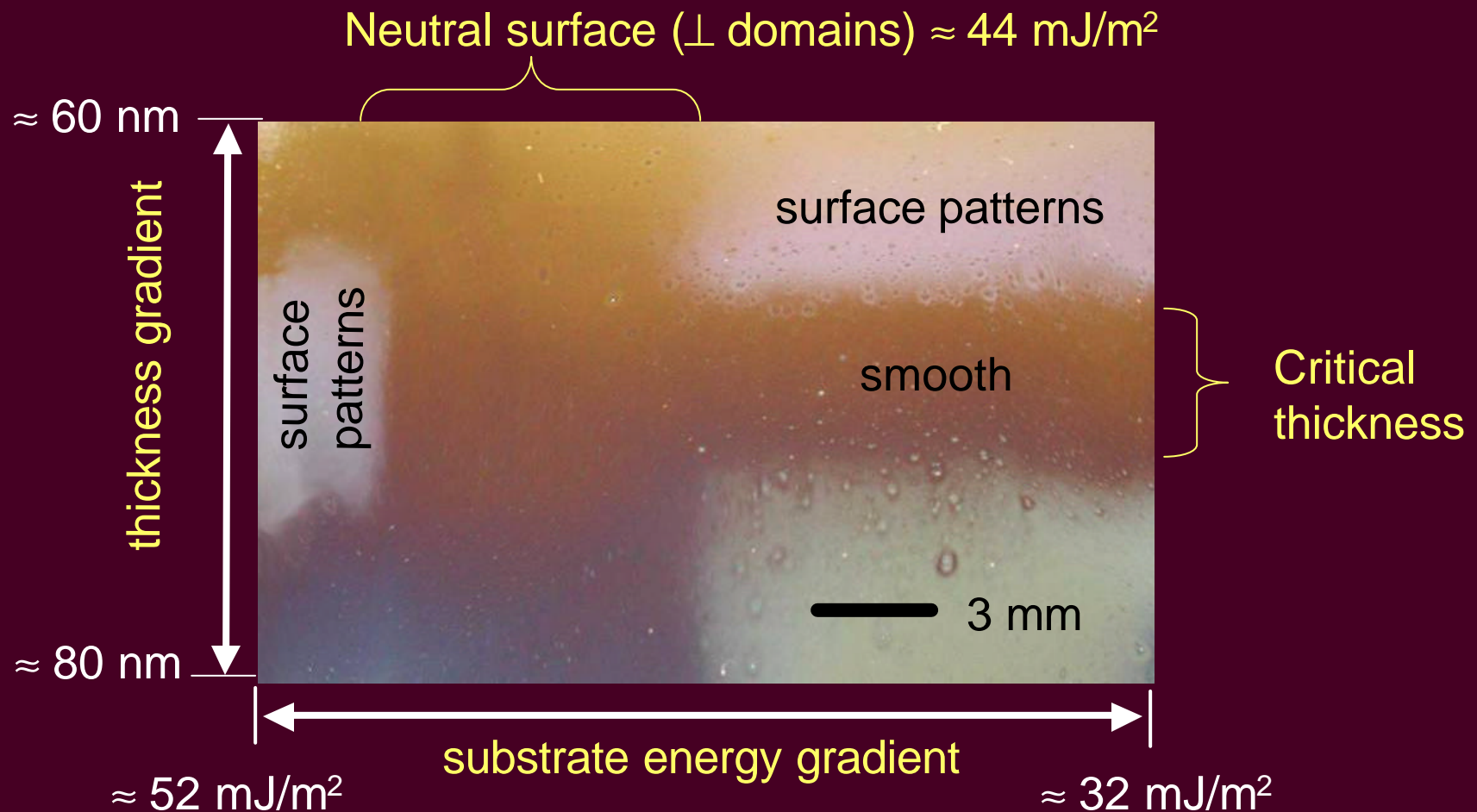


# Mapping: BC Film Gradient Combi Library

A.P. Smith et al, Macromolecules Rapid Communications 2003; 24(1): 131

A.P. Smith et al, Physical Review Letters 2001; 8701(1): 5503

Polystyrene-b-Polymethylmethacryate film (After T.P. Russell)





# Optimization: BC Film Gradient on Patterned Substrate

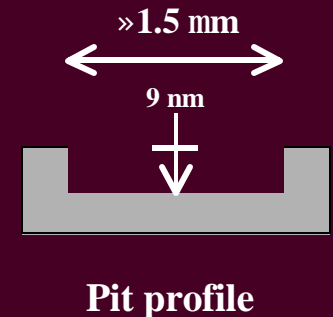
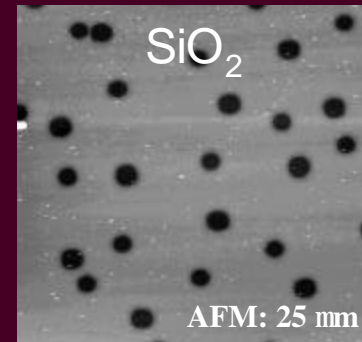
M.J. Fasolka, T.A. Germer, A. Karim, & E.J. Amis, NIST

## Goals:

- Map behavior of BC Films on topographically structured substrates
- Find conditions for “anti-conformal” film on a specific substrate

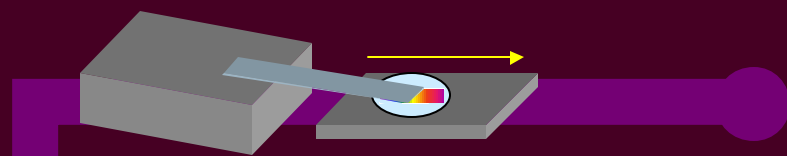


Pseudo random array of pits



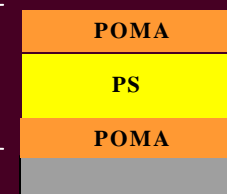
## High-throughput Gradient Experiment:

Thickness Gradient Fabrication



Polystyrene-b-Poly(n-octyl methacrylate)

Lamellar period  
 $L_0 = 23\text{nm}$



goal



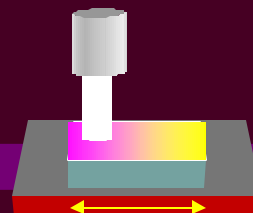
2 specimens



35+ test points

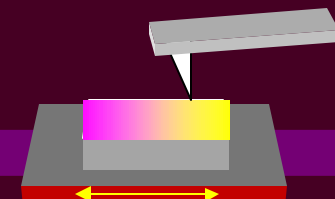


Auto Interferometry

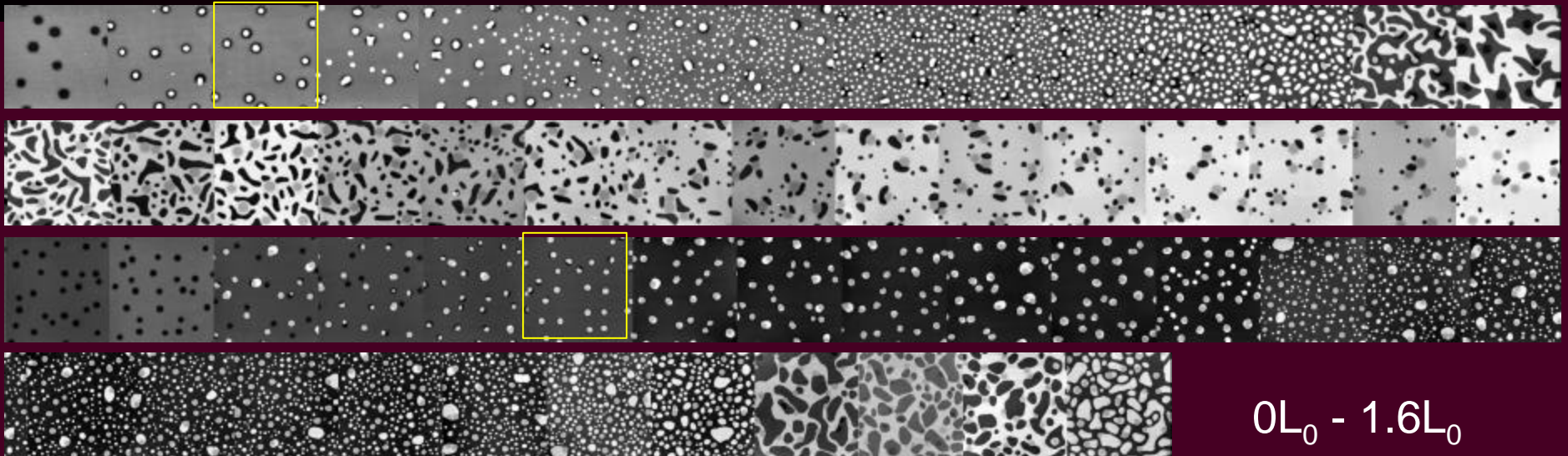


24hr @  
180 °C

Auto AFM

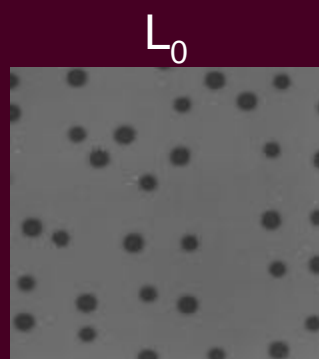


# Optimization: BC Film Gradient on Patterned Substrate

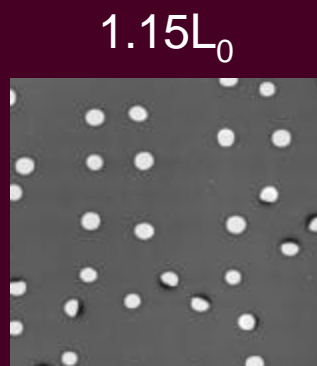


$0L_0 - 1.6L_0$

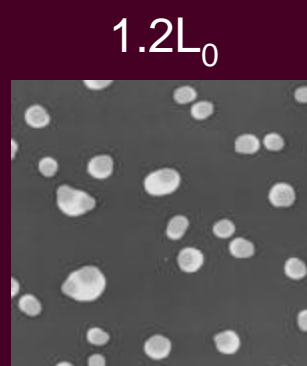
Rich thickness-dependent behavior:



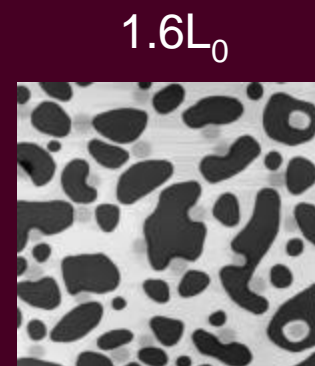
Conformal



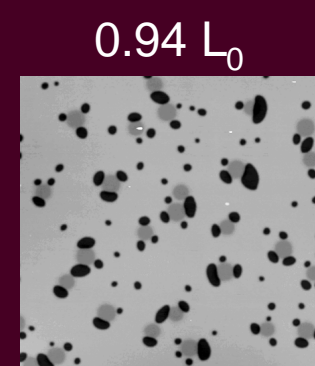
Anti-conformal



Anti-conformal  
+  
Non-conformal



Non-conformal  
+  
Conformal

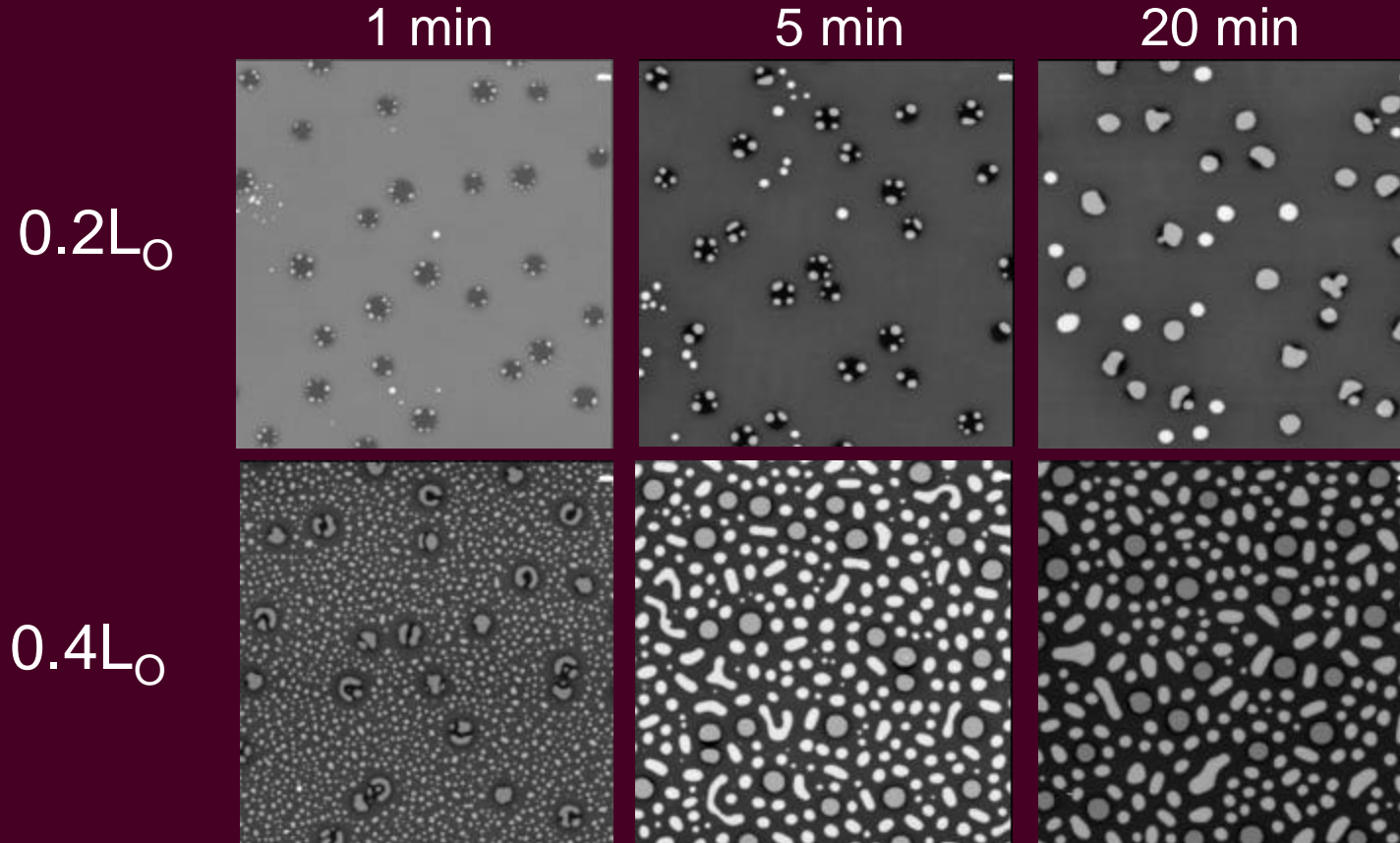
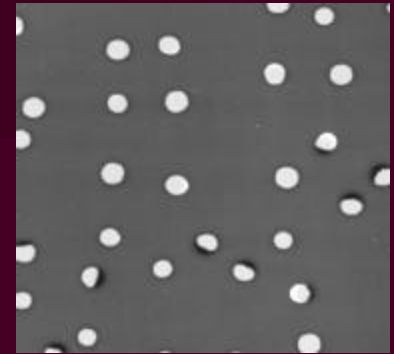


Hole clustering

# BC Film on Patterned Substrate

When and Why do anti-conformal films occur?

- Island area equals pit area ( $15\% \text{ pit area} \Rightarrow 0.15nL_0$ )
- Pits nucleate islands

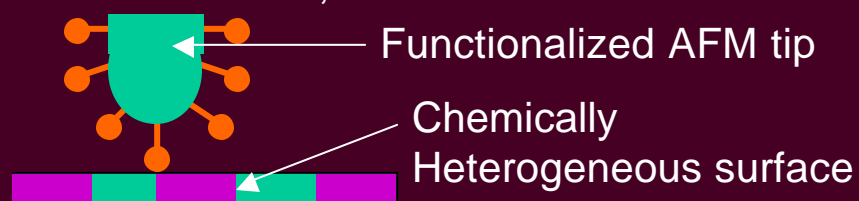


# Measurements: Gradient Reference Substrate for CFM

M.J. Fasolka, T. Nguyen, A. Karim, K. Briggman, NIST

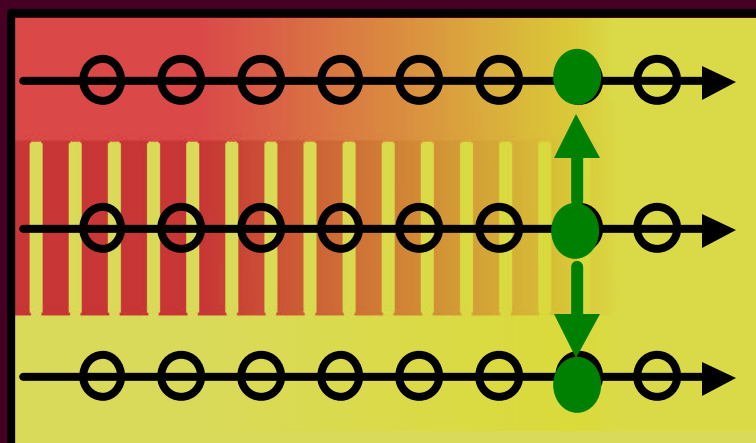
Advance *Chemical Force Microscopy* as a quantitative measurement technique

C. M. Lieber, Harvard



Reference Specimens that:

- Calibrate image contrast
- Challenge sensitivity



Contact  $\angle$

CFM done here  
15 nm pitch lines

Contact  $\angle$

- Chemical contrast gradient
- Relates contrast to traditional analysis
- Gauges sensitivity

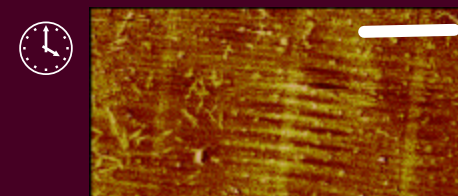
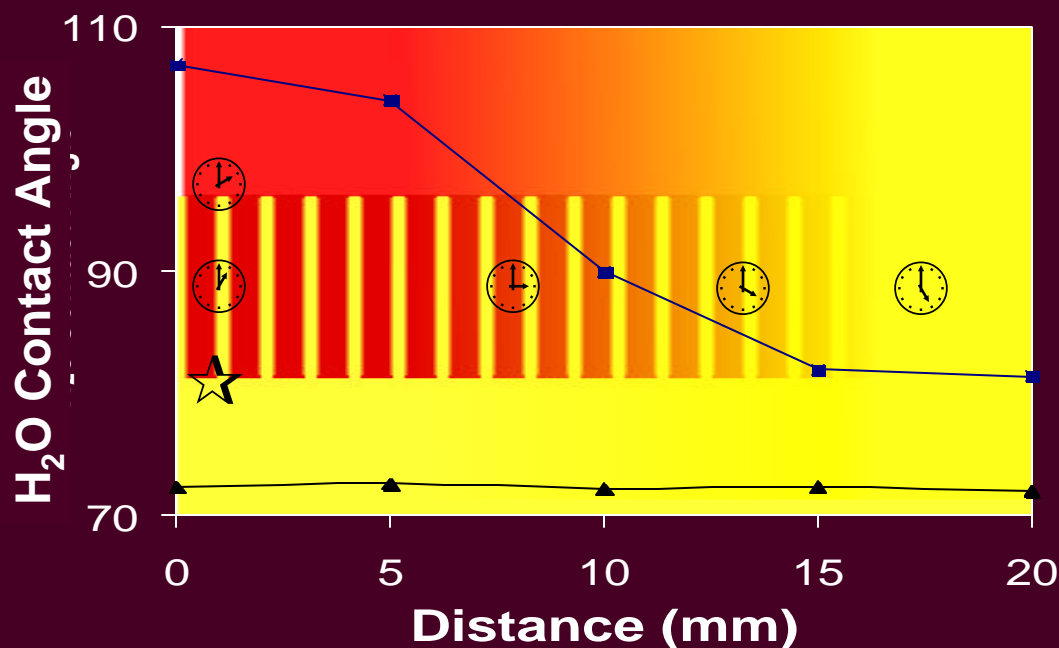
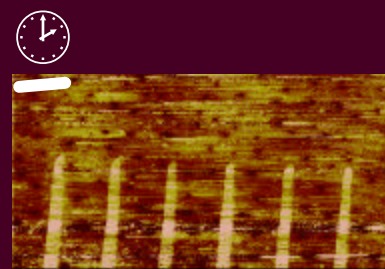
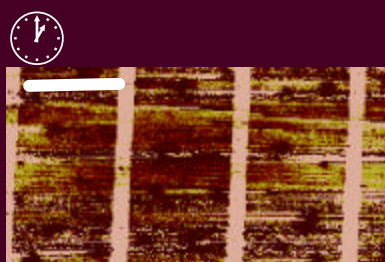
## Fabrication and Calibration of Specimen

- **Hydrophilic** and **Hydrophobic** SAMs printed with PDMS stamp
- *Gradient in UV exposure* gradually converts hydrophobic SAM to hydrophilic species.
- Contact  $\angle$  measurements calibrate contrast in the patterned area.



# Measurements: Gradient Reference Substrate for CFM

## Contact-Mode Friction AFM Images



Scale bars are 10mm  
Images have equal z-scales

Print:  $(\text{CH}_2)_{17}\text{-CH}_3$  Thiol SAM  
Fill:  $(\text{CH}_2)_{15}\text{-COOH}$  Thiol SAM

Linear UV Exposure Ramp: 0 - 60s

# Summary: Gradients for Nanotechnology

## NIST Combinatorial Methods Center Capabilities:

- Purpose and Scope
- Gradient Tool Box Examples
  - Thickness
  - Surface Energy
  - Temperature and others



## Utility of Gradients for Nanotechnology Development

- Thorough Behavior Mapping  
*Ultra-high information density BC Film Library*
- Process or Parameter Optimization  
*Determination of conditions for anti-conformal films*
- Advancement of Nano-scale Measurements  
*Reference Substrates for Chemical Force Microscopy*

# Contributors



## The NIST Combi Methods Center Core Team:

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Howard Walls  
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Chris Harrison (Schlumberge)  
Carson Meredith (GA Tech)



## NIST Collaborators on Examples:

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Kimberly Briggman (Optical Technology Division)  
Tihn Nguyen (Building and Fire Research)



# Advertisements: *(ask for a CD)*



## Interested in Combinatorial and High-Throughput Materials Research?

*Post-doctoral Positions are Available!*

- Combi and HTE for Polymers and Nanotechnology
- Excellent opportunities for industrial interaction

**Contact: Michael Fasolka at [mfasolka@nist.gov](mailto:mfasolka@nist.gov)**

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